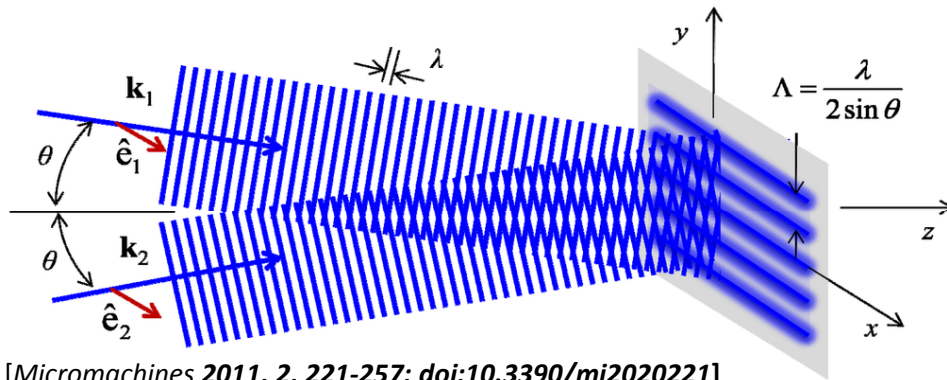


# One beam scanning

- Merit: Better SNR
- Demerit: Contrast defect by different incident angle



[*Micromachines* 2011, 2, 221-257; doi:10.3390/mi2020221]

